

# Photoemission Modeling of the High Brightness Electron Bunch for E-XFEL Applications



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**DESY-TEMF Collaboration Meeting**  
**Lecture Room S2|17-103, TEMF, TU Darmstadt**  
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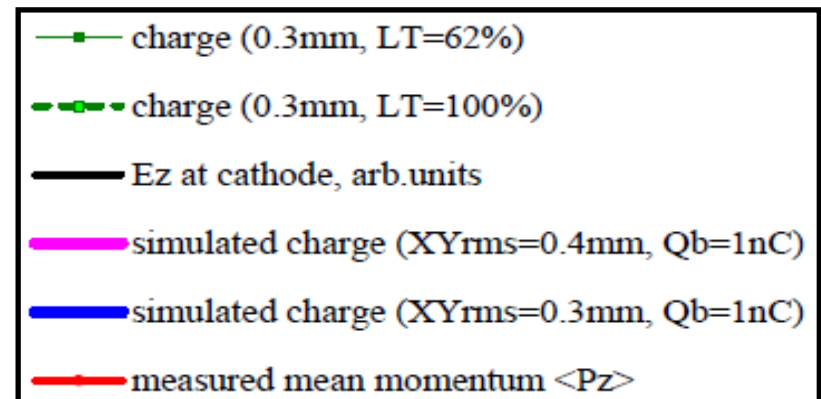
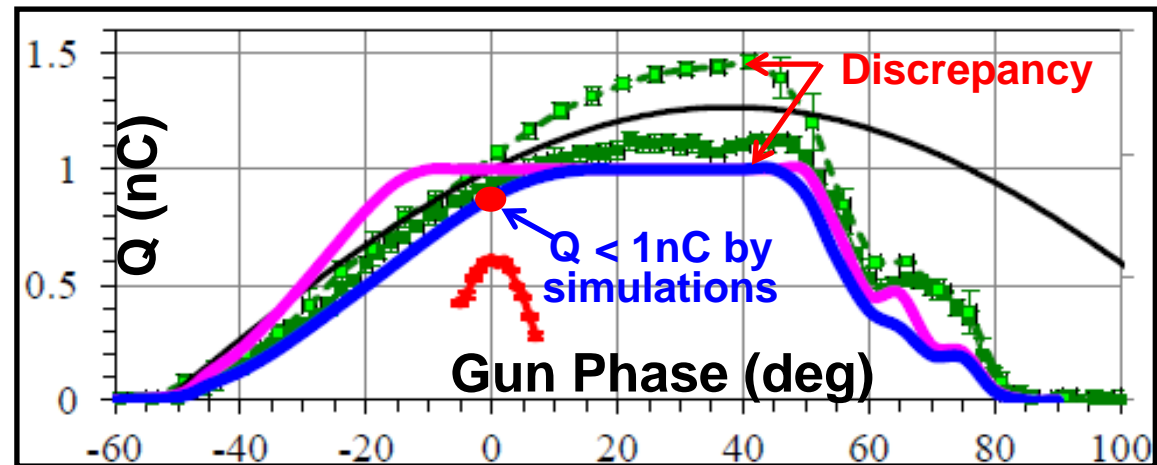
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# Introduction: motivation

- **Discrepancy of the total extracted bunch charge** in between experiments and simulations.
- **Space charge limit** predicted by previous simulations at less than 1 nC for  $XY_{rms} = 0.3$  mm, whereas 1 nC and even higher bunch charges were detected experimentally.

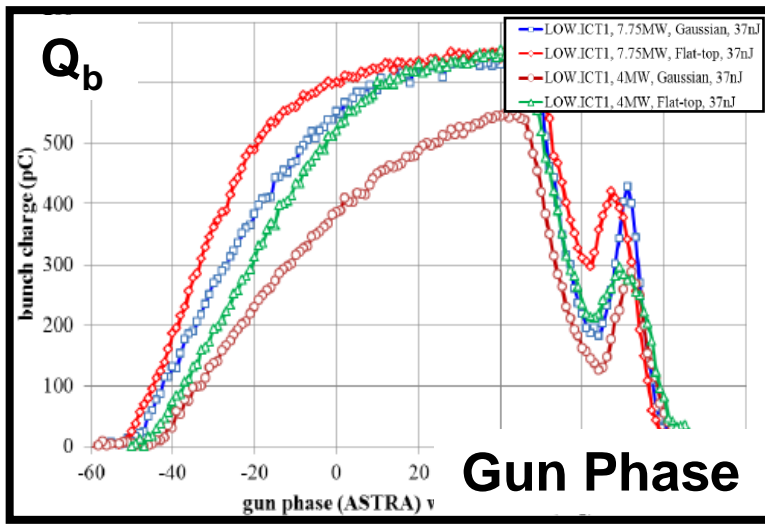
## Total Emitted Bunch Charge vs. Launch Phase



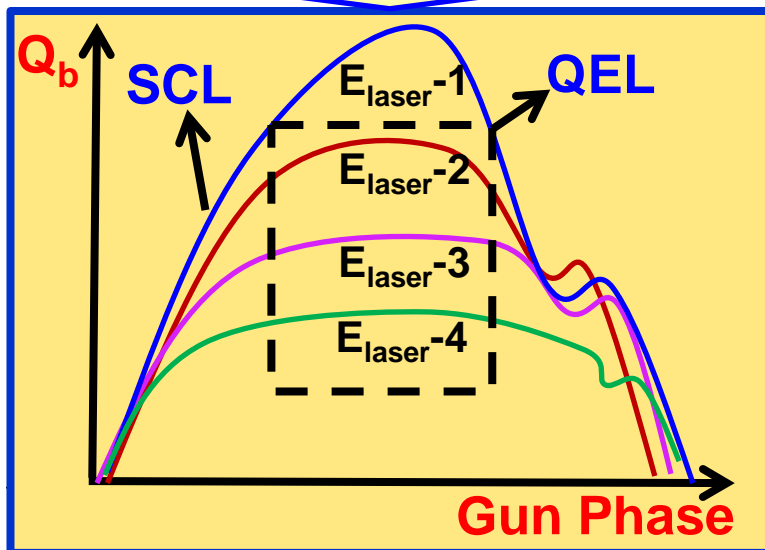
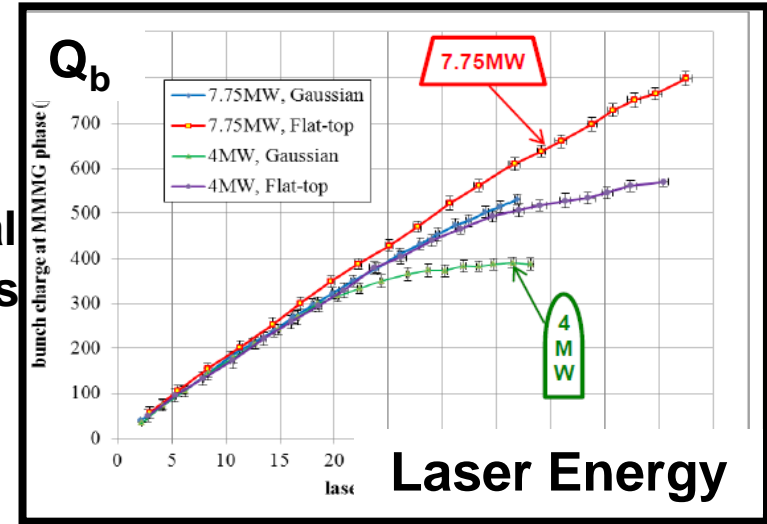
### Objectives:

1. Find out the discrepancy source from the simulation side
2. Improve the beam dynamics modeling of the bunch emission process

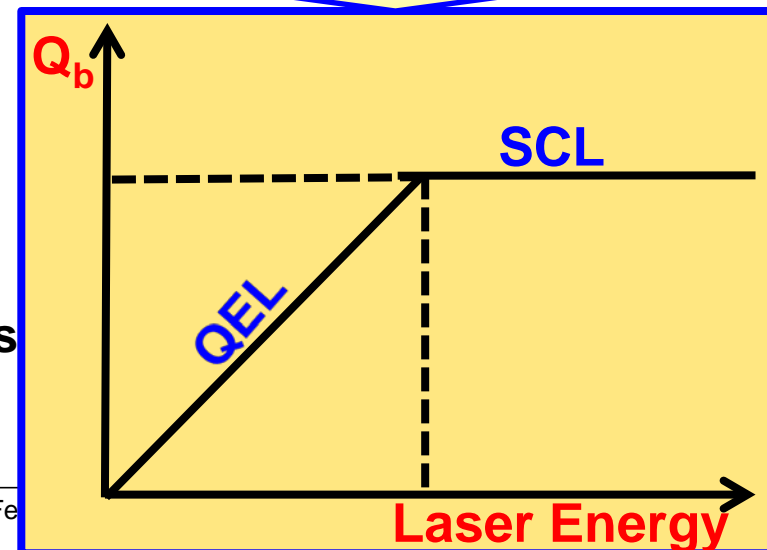
# Introduction: from observations to assumptions



Experimental  
Observations



Simulation  
Assumptions



# Introduction: from observations to assumptions

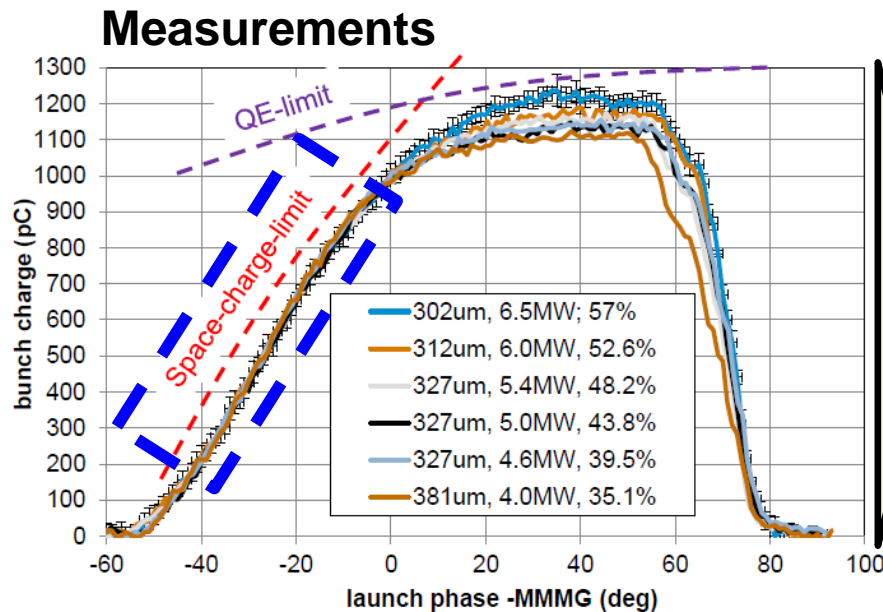
- **Space Charge Limited (SCL) Regime:**
  - **Main Idea:** assuming that the emission source just provides the maximum number of particles that allows the beam to propagate without reflected particles (space charge limit calculation)
  - **Simulation Method:** “Bunch Charge Iteration Algorithm”
- **Quantum Efficiency Limited (QEL) Regime:**
  - **Main Idea:** assuming a time-dependent emission where the initial charge distribution needs to be modified due to the transient effects during emission (time-dependent QE)
  - **Simulation Method:** "Temporal Profile Iteration Algorithm"

## Bunch Charge Extractions in the SCL Regime

*(see the simulation algorithm from YC's talk at DESY Hamburg, 09.07.2014)*

- **Algorithm validation:** considering different laser spot sizes ( $\sigma_{xy}$ ), accelerating field gradients (Ecath), laser transmissions (LT) and temporal laser profiles (FT/GS) for SCL simulations

# Simulations vs. Measurements



## Simultaneous variations of multiple parameters

Experiment 1 to 6	#	$\sigma_{xy}$ /mm	LT	$P_{rf, gun}$ /MW	$\sqrt{P_{rf, gun} \times \sigma_{xy}}$
	1	0.302	57%	6.49	0.769
	2	0.312	52.6%	5.99	0.764
	3	0.327	48.2%	5.45	0.763
	4	0.341	43.8%	5.00	0.762
	5	0.361	39.5%	4.55	0.770
	6	0.382	35.1%	3.99	0.762

laser spot size  $\sigma_{xy}$

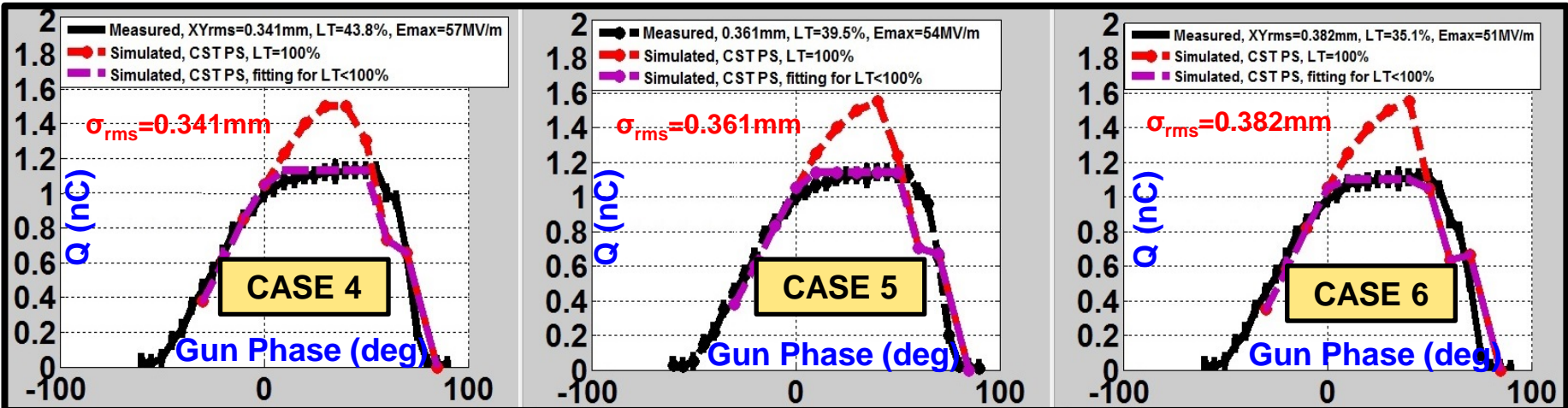
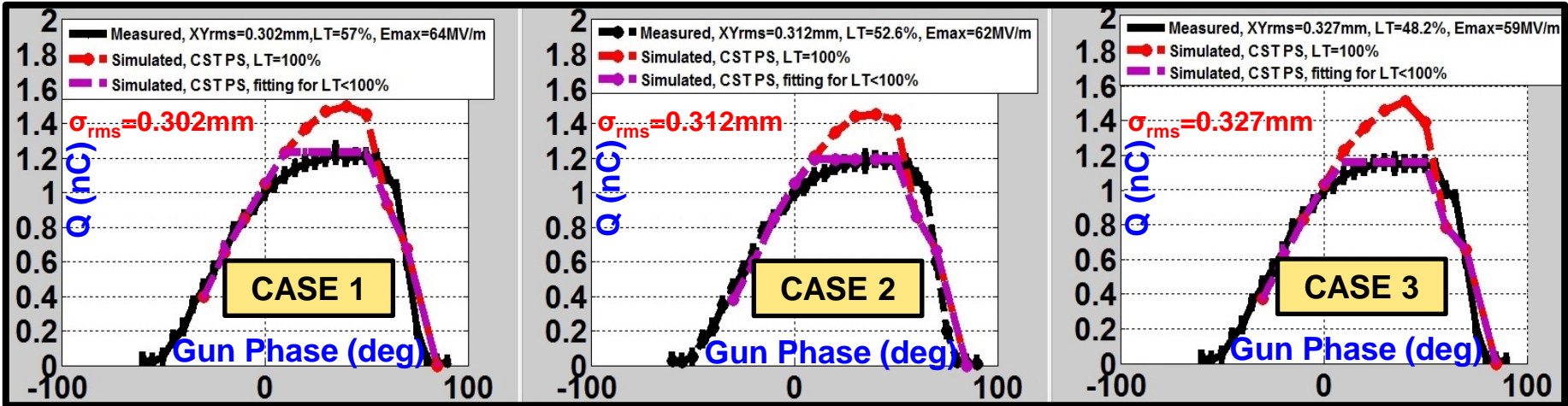
RF power  $P_{rf, gun}$

Laser transmission LT

1. Reproduce the six measurements in simulations
2. Compare the total bunch charge with measurements **in the SCL regime**

# Simulations vs. Measurements

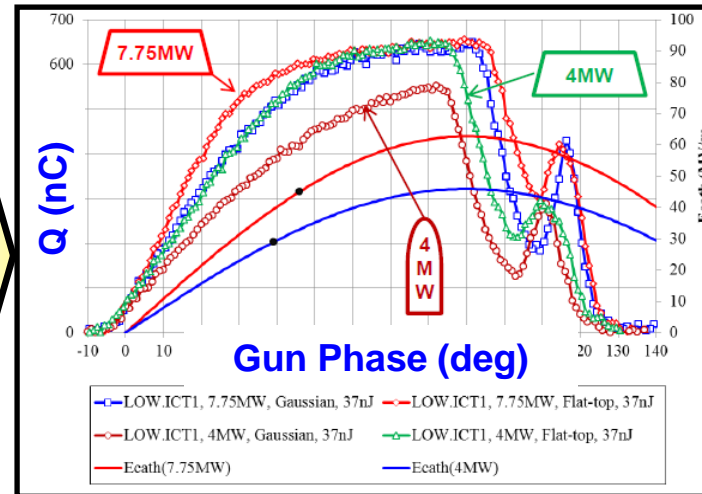
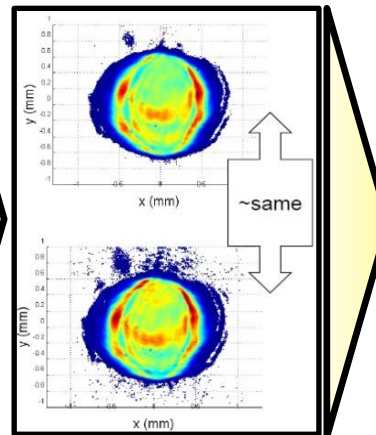
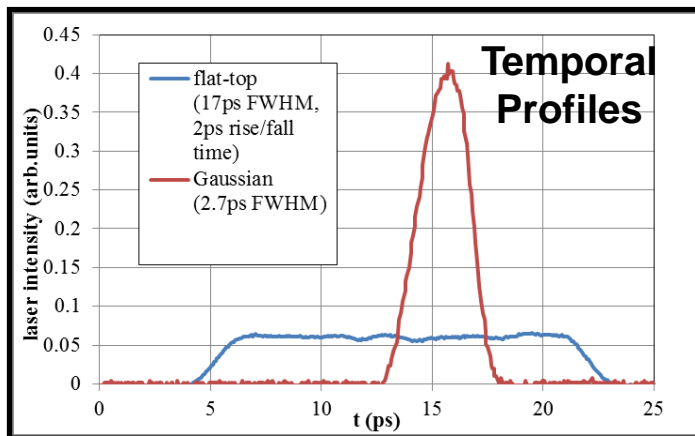
..... Measurement; ..... Simulation (100% LTs); ..... Simulation (lower LTs)





# Simulations vs. Measurements

Further validation by considering different temporal laser profiles

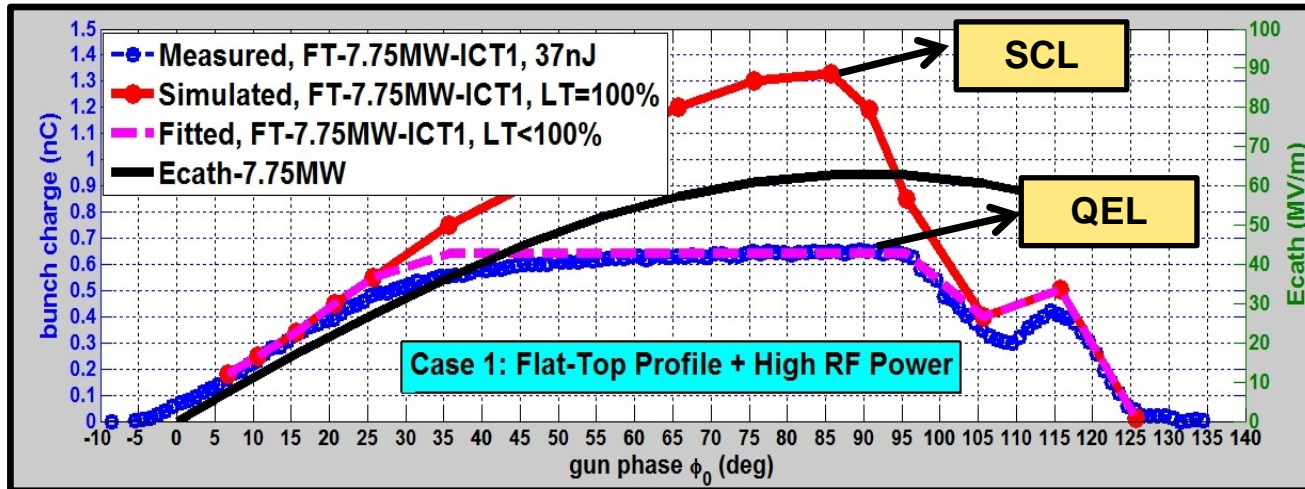


	7.75MW	4MW
Flat-top (17ps)	case 1	case 3
Short Gaussian (2.7ps)	case 2	case 4

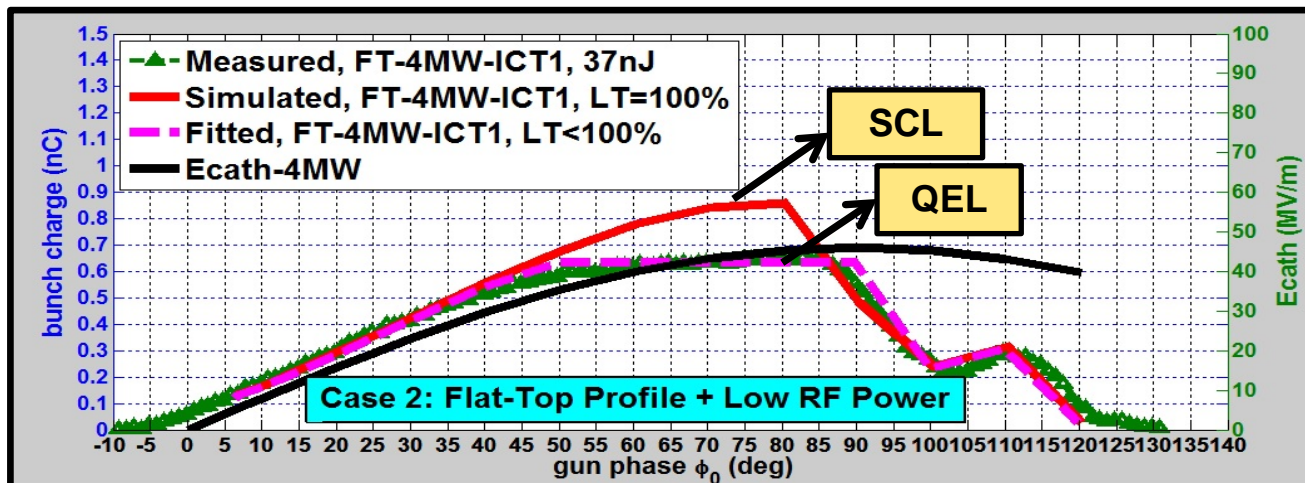
1. Reproduce the four measurements in simulations
2. Compare the total bunch charge with measurements **in the SCL regime**

# Simulations vs. Measurements

1.



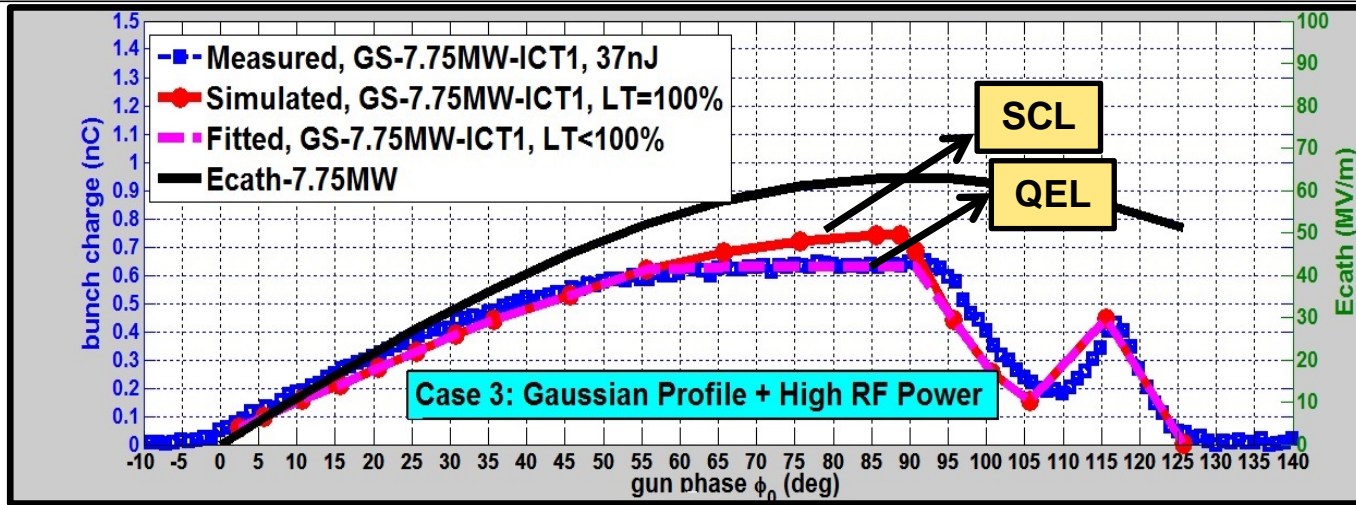
2.



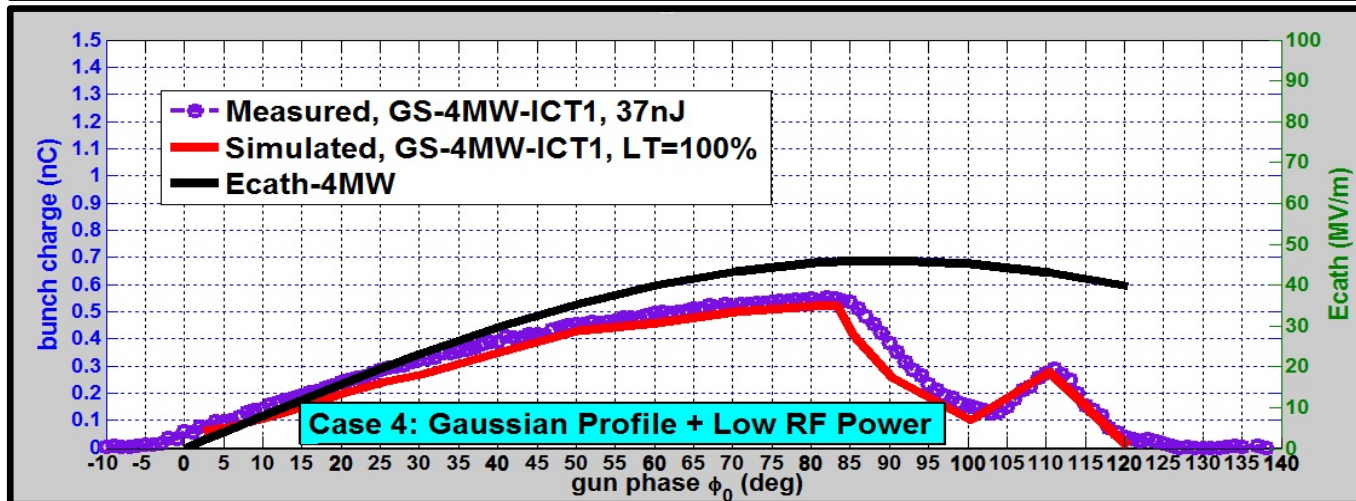
Flat-top Profile (FWHM: 17ps)

# Simulations vs. Measurements

3.

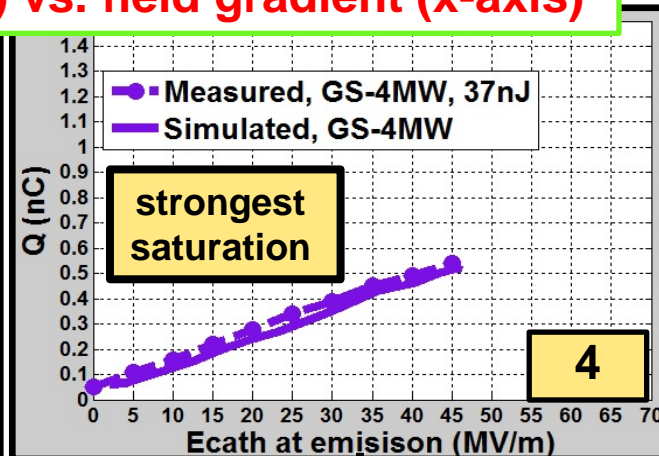
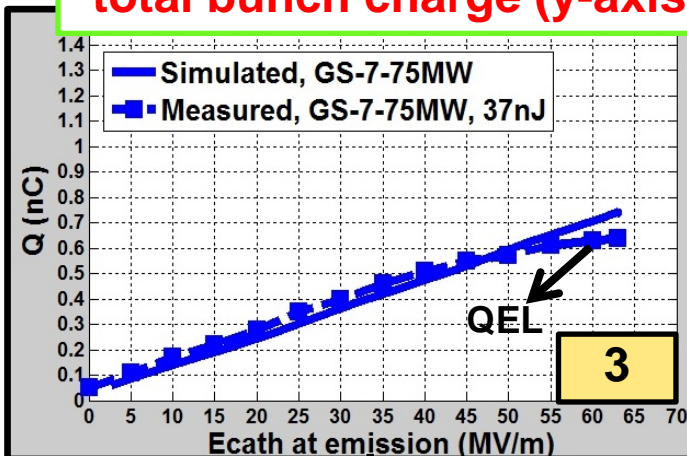
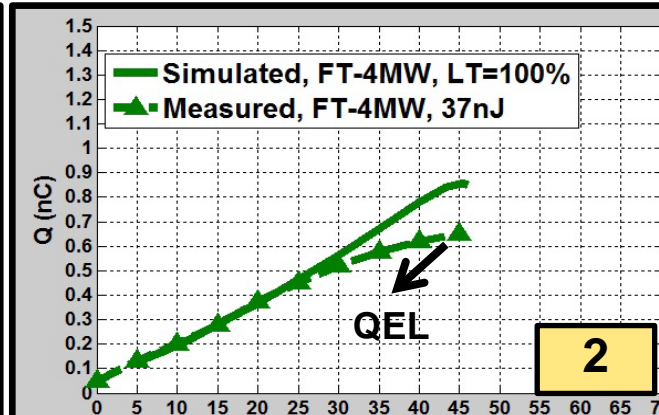
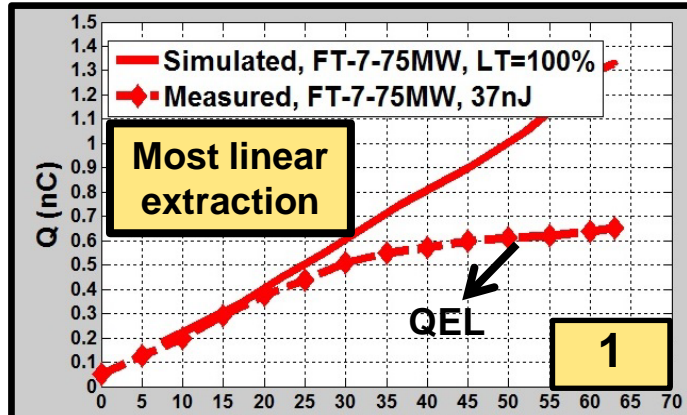


4.



Short Gaussian Profile (FWHM: 2.7ps)

# Simulations vs. Measurements



total bunch charge (y-axis) vs. field gradient (x-axis)

- SCL to QEL transition:
  - 1: FT + 7.75 MW
  - 2: FT + 4 MW
  - 3: GS + 7.75 MW
- Strongest saturation :
  - 4: GS + 4MW

closest to SCL
- Most linear extraction:
  - 1: FT + 7.75MW

# Intermediate Summary

1. **Measurements at the space charge limits** with all machine parameters can be reproduced correctly by full-wave PIC simulations, but not by Astra.
2. "**Bunch Charge Iteration Algorithm**" has been proposed and verified based on the self-consistent emission model of CST-PS.
3. **Comparison results** have shown, that the transverse profile of the bunch does not play a critical role in the bunch charge studies.

# Analysis of Effective Bunch Size at Emission by SCL Emission Models (new)

(Investigations on **the shift of the laser spot size**  
for the optimum emittance at EMSY1)

- Model A: 1-D Parallel Plate Capacitor (PPC)
- Model B: 2-D C-L Scaling Law Based on PIC Simulations
- Model C: 2-D Analytical C-L Scaling Law

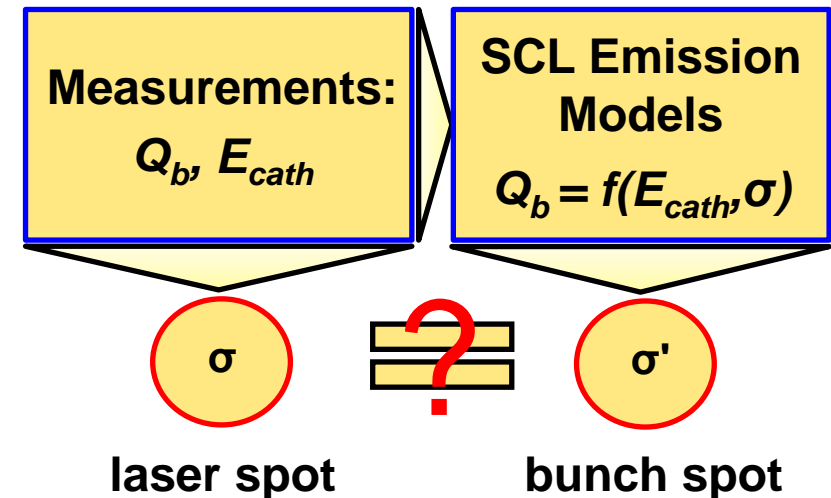
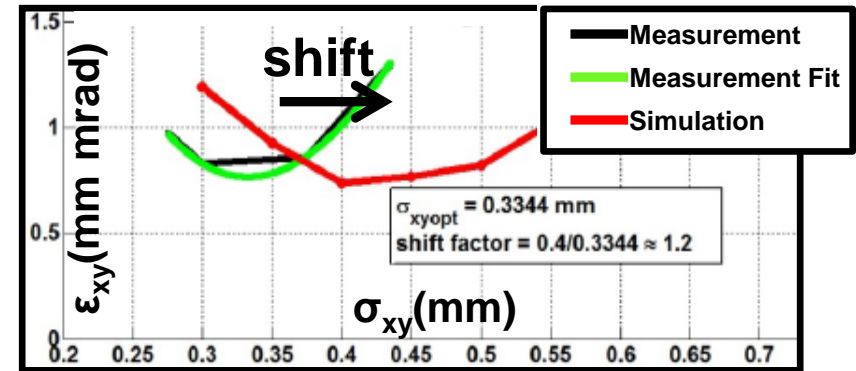
# Motivation

- The optimum laser spot size for minimum emittance at EMSY1 was found at  $\sim 0.3$  mm rms, however, all simulations predict an optimum spot size of 0.4 mm rms for 1 nC case.
- $Q = 1$  nC,  $XY_{rms} = 0.3$  mm, close to the space charge limit
- New charge simulations by CST-PS have shown good agreements with measurements at the space charge limits.

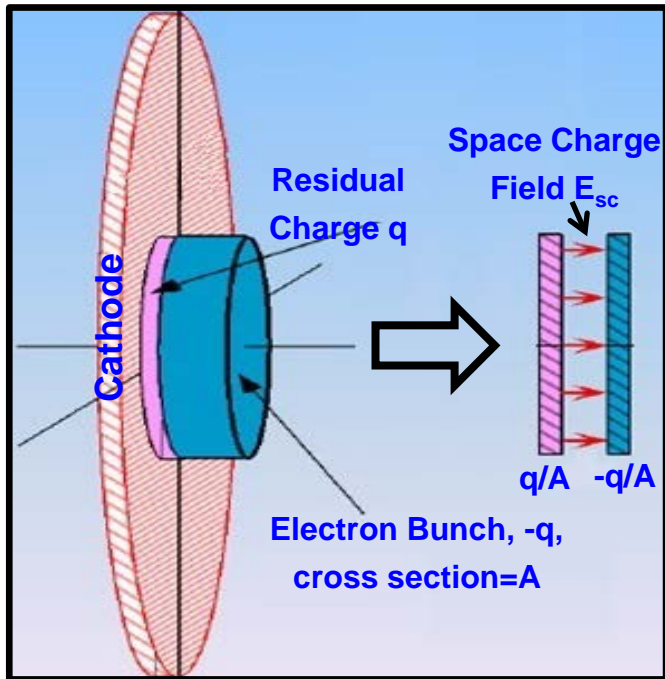
$$\text{shift factor}(SF) = \frac{\text{effective bunch size}}{\text{laser spot size}}$$

**Observation:  $SF \approx 1.2$**

Emittance vs. Laser Spot Size



# Model A: 1D Parallel Plate Capacitor (PPC)



SC field:  $E_{sc} = \sigma / \epsilon_0$

SCL occurs when  $E_{sc} = E_{rf}$

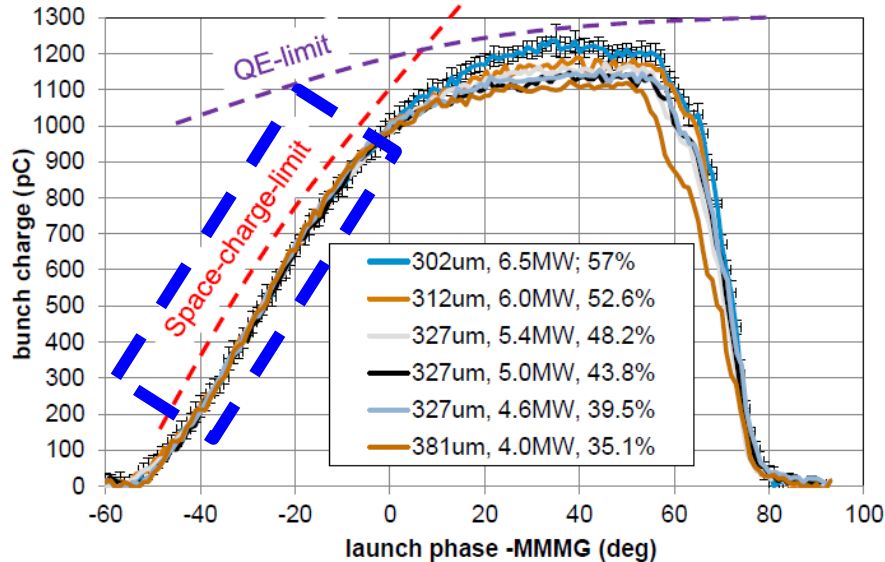
Limiting charge density:  $\sigma_{scl} = \epsilon_0 E_{rf}$

Emitted charge:  $Q = \pi R^2 \epsilon_0 E_{rf} \sin \phi_{rf}$

**R: effective bunch size, should be found by measurements**




# Model A: 1D Parallel Plate Capacitor (PPC)

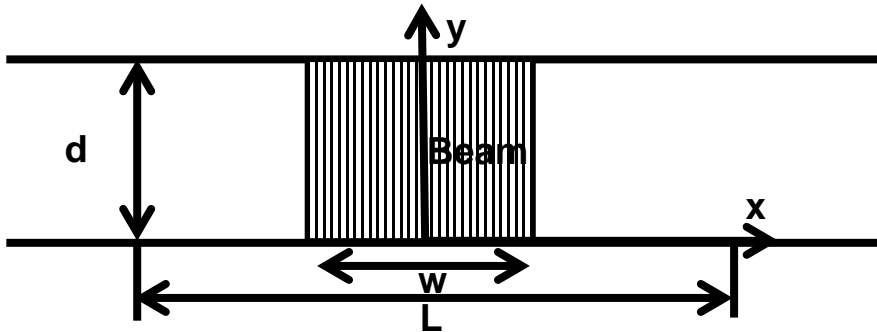


#	Laser Spot Size $\sigma_{xy}$ (mm in rms)	Effective Radius $R_{eff}$ (mm in rms)	Shift Factor = $R_{eff} / \sigma_{xy}$
1	0.302	0.4478	1.483
2	0.312	0.4603	1.475
3	0.327	0.4775	1.460
4	0.341	0.4908	1.439
5	0.361	0.5060	1.402
6	0.382	0.5322	1.393

Experiment 1 to 6	#	$\sigma_{xy}$ /mm	LT**	$P_{rf, gun}$ /MW	$\sqrt{P_{rf, gun}} \times \sigma_{xy}$
	1	0.302	57%	6.49	0.769
	2	0.312	52.6%	5.99	0.764
	3	0.327	48.2%	5.45	0.763
	4	0.341	43.8%	5.00	0.762
	5	0.361	39.5%	4.55	0.770
	6	0.382	35.1%	3.99	0.762

- PPC model fits the measurement data with **a prediction of larger effective bunch size** than laser spot size
- The shift factor is  $\sim 1.45 > 1.2$
- PPC model is only in 1D, apparently **not accurate enough!**  **2D Models**

# Model B: 2D C-L Scaling Law based on PIC Simulations



**C-L Law:**  $J_{SCL-1D} = \frac{4\epsilon_0}{9} \sqrt{\frac{2e}{m}} \frac{V_0^{3/2}}{d^2}$

**Scaling Law for finite transverse dimension:**

$$\frac{J_{SCL-2D}}{J_{SCL-1D}} = 1 + \frac{0.3145}{w/d} + \frac{0.0004}{(w/d)^2}$$

$$V_0 = E_0 d, \quad d = \frac{eE_0}{2m} \Delta t^2$$

**d:** bunch extension length to effective diode

**w:** width of emission,  $2 \cdot R$

$$Q_{SCL-2D} = \frac{8}{9} \pi \epsilon_0 E_0 \times (R^2 + 0.15725Rd + 0.0001d^2)$$

#	Laser Spot Size $\sigma_{xy}$ (mm, rms)	Effective Radius $R_{eff}$ (mm, rms)	Shift Factor = $R_{eff} / \sigma_{xy}$	R-square of Fitting
1	0.302	0.332	1.099	0.970
2	0.312	0.346	1.109	0.969
3	0.327	0.368	1.125	0.966
4	0.341	0.385	1.129	0.963
5	0.361	0.404	1.119	0.959
6	0.382	0.436	1.141	0.949

– Predicted spot size > laser spot size

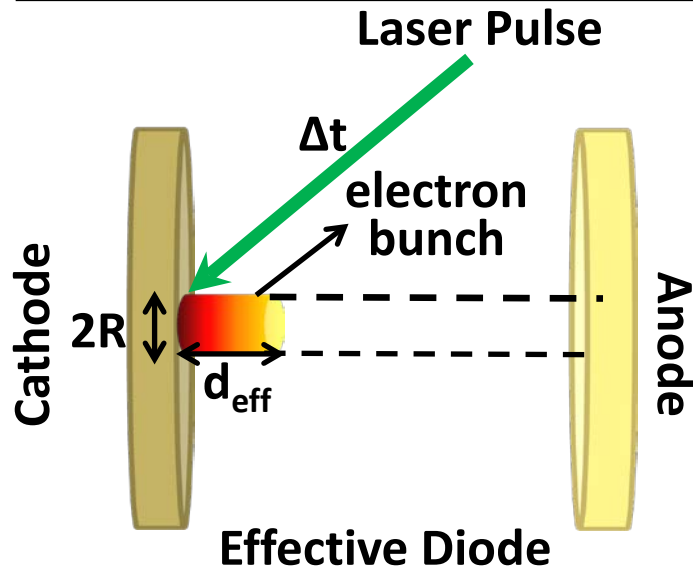
– Shift factor ~ 1.1 < 1.2

– **Model B is in 2D, but the length of the effective diode is fixed for all the cases, which results in inaccuracies.**



**2D Model with unfixed  $d_{eff}$**

# Model C: 2D C-L Scaling Law



Define **an effective diode of length  $d_{\text{eff}}$** ,  
and apply the **C-L law** to the new diode geometry.

**C-L law:**  $J \sim V_0^{1.5}$   
 $\sim d^{-2}$

**Finite Transverse  
Dimensions**

$$Q_{SCL-2D} = I_{SCL-2D} \Delta t$$

$$= \frac{\sqrt{2}}{9} \frac{I_0 R^2}{\sqrt{d_{\text{eff}}}} \left( \frac{eE_0}{mc^2} \right)^{1.5} \Delta t$$

$d = d_{\text{eff}}$

$V_0 = E_0 d_{\text{eff}}$

R: beam radius

$\Delta t$ : length of laser pulse

c: speed of light

$I_0$ : constant, 17kA

#	Laser Spot Size (mm in rms)	Fitted Radius (mm in rms)	Shift Factor	$d_{\text{eff}}$ (mm)	R-square of Fitting
1	0.302	0.372	1.232	1.63	0.9441
2	0.312	0.382	1.224	1.55	0.9333
3	0.327	0.392	1.199	1.39	0.9168
4	0.341	0.406	1.191	1.37	0.9023
5	0.361	0.419	1.159	1.26	0.8831
6	0.382	0.432	1.131	1.10	0.8459

# Analysis of Effective Bunch Size at Emission

## – Estimations of Emission Spot Size with Different Analytical Models at SCL

#	Laser Spot Size (mm in rms)	Shift Factor = Fitted Spot Size / Laser Spot Size		
		1-D PPC	2-D C-L (PIC)	2-D C-L (Analytical)
1	0.302	1.483	1.099	1.232
2	0.312	1.475	1.109	1.224
3	0.327	1.460	1.125	1.199
4	0.341	1.439	1.129	1.191
5	0.361	1.402	1.119	1.159
6	0.382	1.393	1.141	1.131

Length of the  
Effective Diode

$d_{\text{eff}}$ (mm)
1.63
1.55
1.39
1.37
1.26
1.10

- Predicted spot size > laser spot size
- Shift factor **1.232  $\approx$  1.2**
- **Model C predicts a most comparable shift factor as observation at EMSY1**

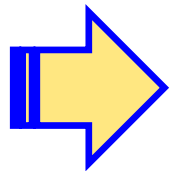
# Intermediate Summary

1. **The shift** of the laser spot size for minimum emittance at EMSY1 can be explained by the 2D C-L Law analytically.
2. Simulation prediction fits the theory of SCL emission which indicates **the shifting is unlikely physical** but seems coming from **measurement issues**.
3. For that reason, relevant experimental issues in terms of the laser spot size measurement need to be checked.

## Quantum Efficiency Limited (QEL) Emission (new)

## In QE-Limited Regime,

1. QE strongly depends on **the fields at the cathode** surface and becomes time-dependent due to the field effects
2. Production of the electron bunch will then, not only depend on **the cathode drive laser**, but also the **QE of the cathode**
3. Normally the electron bunch at the cathode reproduce the cathode drive laser profile. But now, **the cathode laser pulse profile  $\neq$  the emitted electron bunch profile** because of **a time-dependent QE**



- Transient effects modeling
- Field effects on QE can be determined by the **Schottky effect**
- Time-Dependent emission model will lead to a modified “asymmetric temporal profile” of the drive laser pulse

## **Longitudinal Beam Dynamics Modeling**

# Mathematical Model

## Time-Dependent Emission Modeling

$$(1) \quad QE(t) = \eta [h\nu - (\Phi_{cath} \mp \Delta\Phi(t))]^2$$

**QE behavior**

$$(2) \quad \Delta\Phi(t) = \sqrt{\frac{e^3}{4\pi\epsilon_0} E_{cath}(z=0, t)}$$

**work function reduction  
due to field effects**

$$(3) \quad Q(t) = \int_{-\infty}^t e \frac{P_{laser}(\tau)}{h\nu} QE(\tau) d\tau$$

**total charge produced  
at the cathode**

$\Phi_{cath}$ : work function, 3.5 eV,  $h\nu = 4.81$  eV       $P_{laser}$ : power profile of the laser pulse

$\Delta\Phi(t)$ : modification of the work function       $\eta$ : cathode property constant

$E_{cath}$ : total fields at the cathode surface

" $\mp$ " characterizes the work function variation when the total field changes sign




# Mathematical Model

$\eta$ ,

describing **cathode properties**, which should be found from the specific emission measurement


In theory,  $\eta$  should be exactly identical for the same photocathode under same experimental conditions.

Unknown


$$QE(t) = \underline{\eta} [h\nu - (\Phi_{cath} \mp \Delta\Phi(t))]^2 \quad (1)$$

$$\Delta\Phi(t) = \sqrt{\frac{e^3}{4\pi\epsilon_0} E_{cath}(z=0, t)} \quad (2)$$

$Q_{meas}$

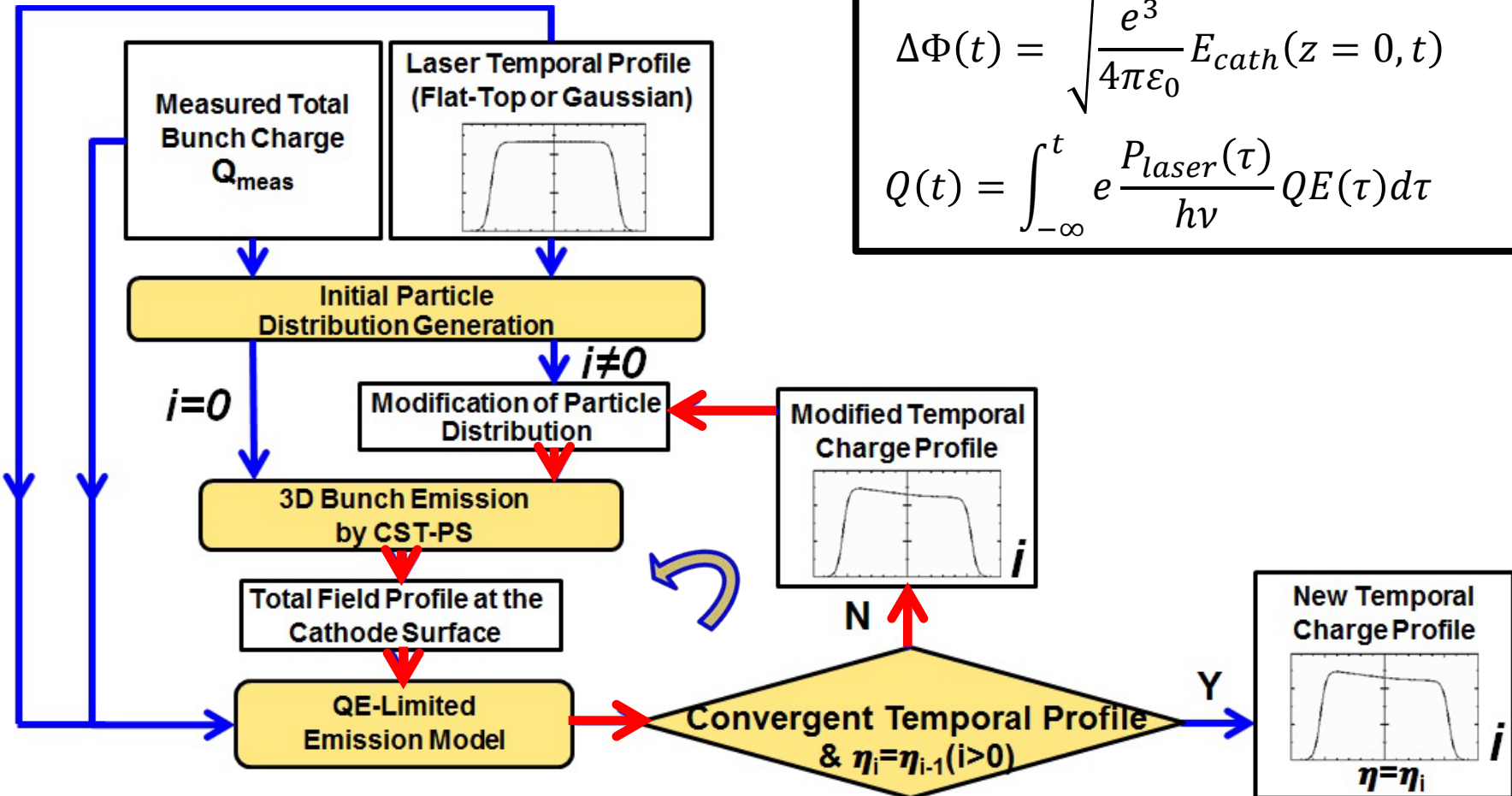

$$Q(t) = \int_{-\infty}^t e \frac{P_{laser}(\tau)}{h\nu} QE(\tau) d\tau \quad (3)$$

➔ **Determining  $\eta$** , by numerically integrating Equations (1) to (3) in the designed simulation loop, **such that Q in Eq. (3) equals to the measured total charge**, then **Q(t) gives the modified temporal profile** accordingly.

➔ **If  $\eta$  is found to be same everywhere**, then the model is correct.

# Simulation Algorithm

## – Consistent Simulation Loop



$$QE(t) = \eta [h\nu - (\Phi_{cath} \mp \Delta\Phi(t))]^2 \quad (1)$$

$$\Delta\Phi(t) = \sqrt{\frac{e^3}{4\pi\epsilon_0} E_{cath}(z=0, t)} \quad (2)$$

$$Q(t) = \int_{-\infty}^t e \frac{P_{laser}(\tau)}{h\nu} QE(\tau) d\tau \quad (3)$$

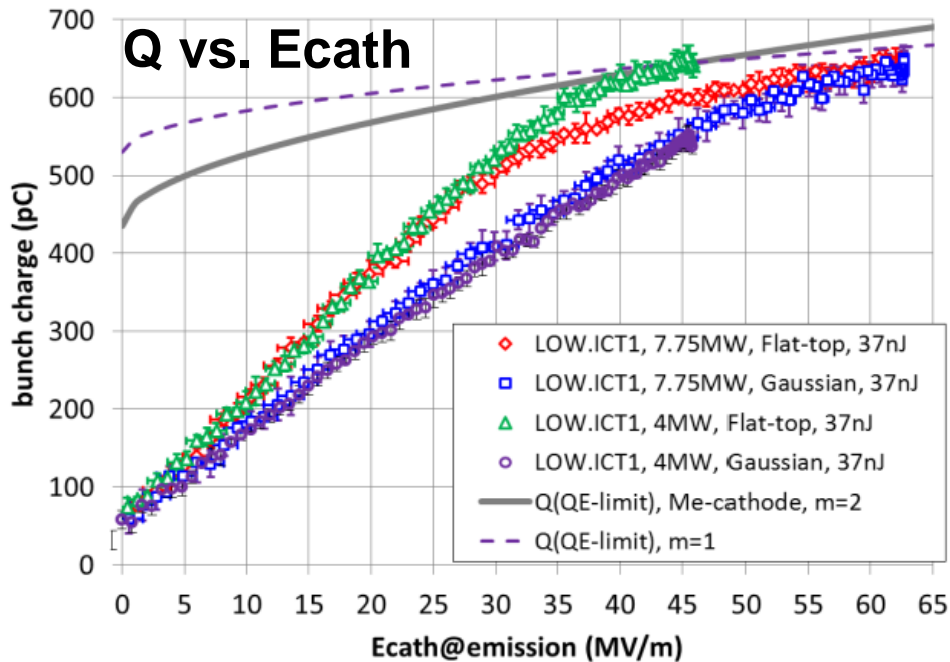
*i: iteration times*

# Comparisons to Measurements

## two typical measurements for injector commissioning

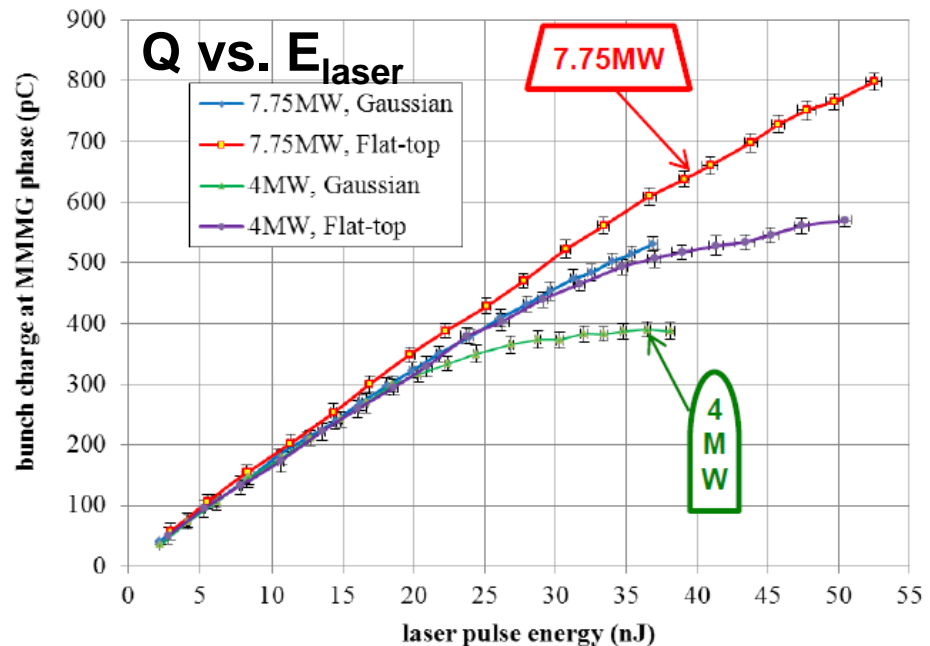
### Measurement A:

Total Charge vs. Field Gradients at  $E_{\text{laser}}=37$  nJ



### Measurement B:

Total Charge vs. Laser Energies at MMMG phase



### 2 Temporal Profiles + 2 Gun Powers

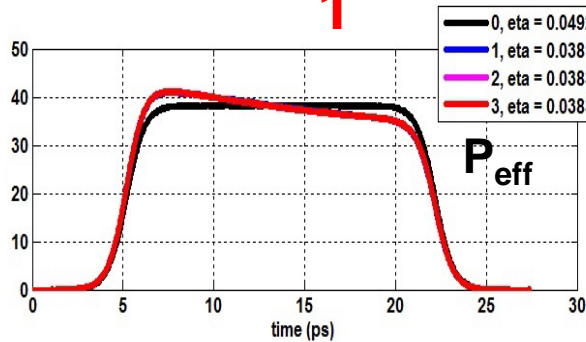
	7.75MW	4MW
Flat-top (17ps)	case 1	case 3
Short Gaussian (2.7ps)	case 2	case 4

1. Reproduce the four measurements in simulations
2. Compare the total bunch charge with measurements in QEL regime

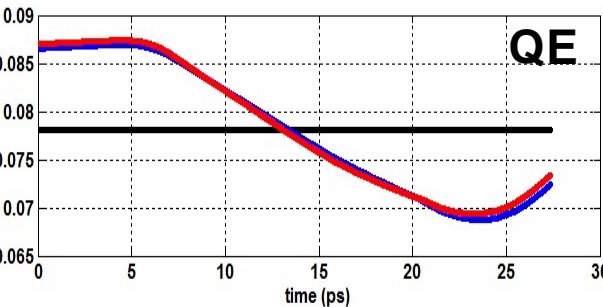
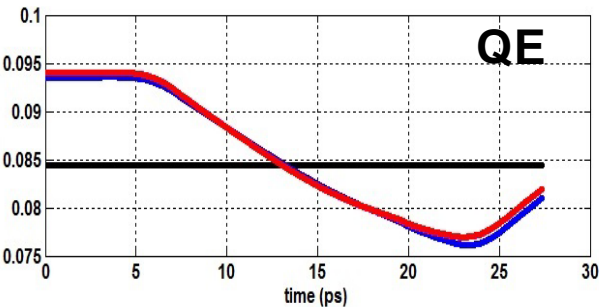
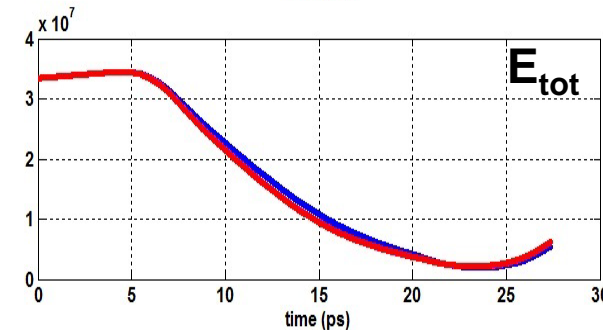
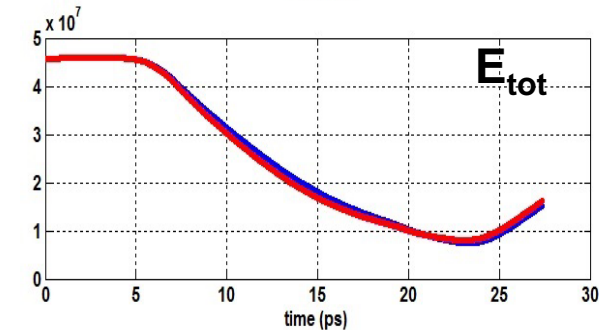
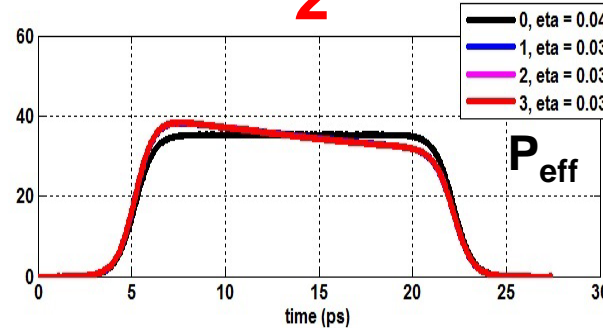
# Simulation Results: applying to different field gradients

## iteration evolution of main parameters

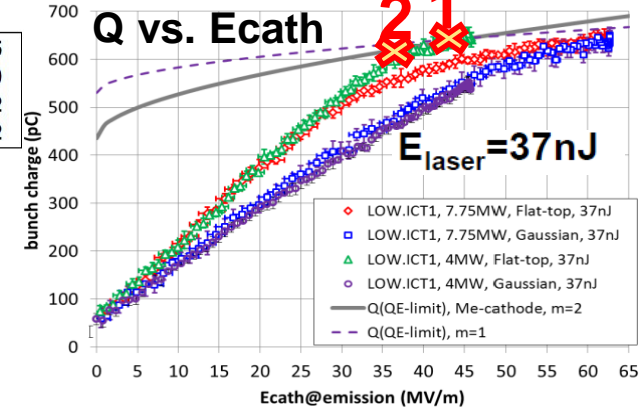
1



2



## Measurement A



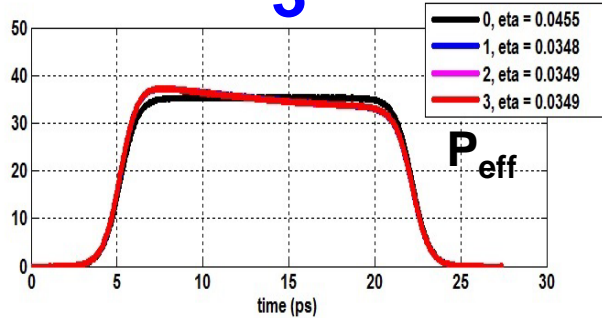
4 MW RF  
Power

	$E_{laser}$ (nJ)	$E_{cath}$ (MV/m)	$\eta$
1	37	~36.7	0.0372
2		~46	0.0383

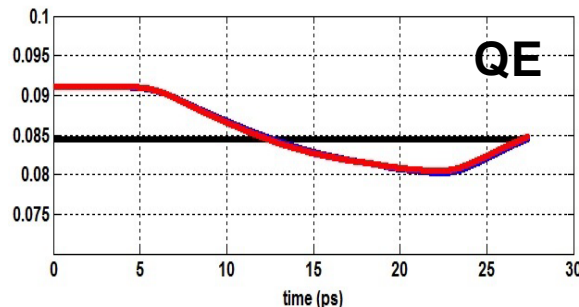
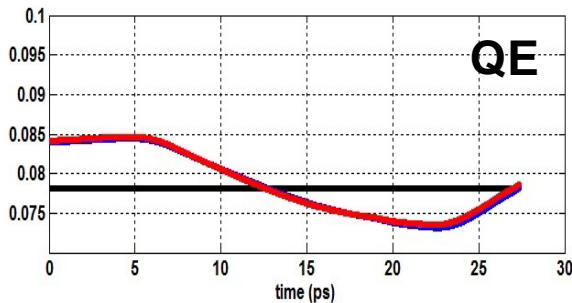
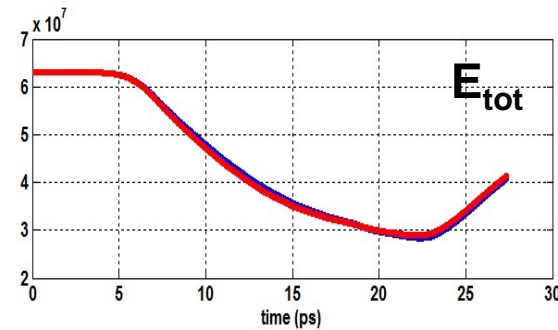
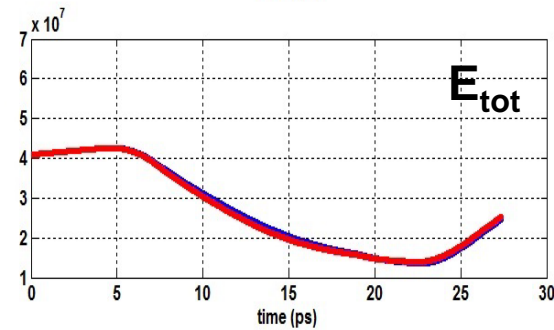
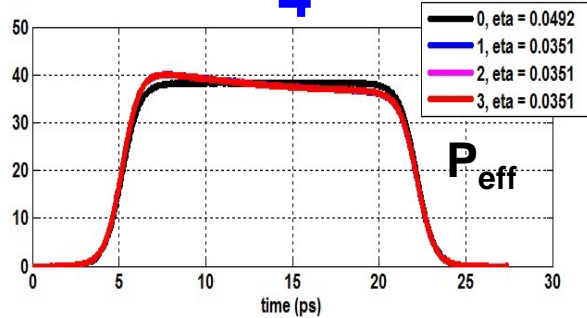
# Simulation Results: applying to different field gradients

## iteration evolution of main parameters

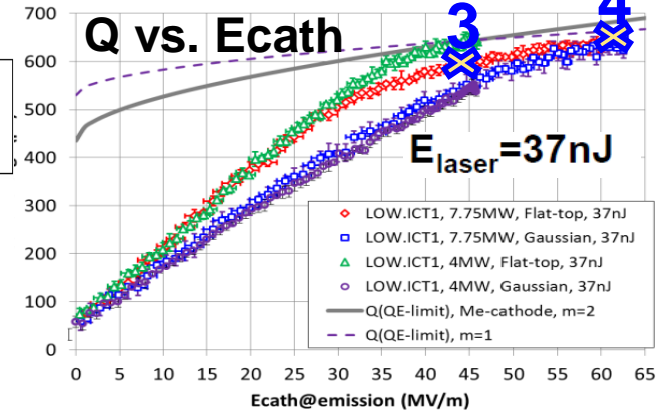
3



4



## Measurement A

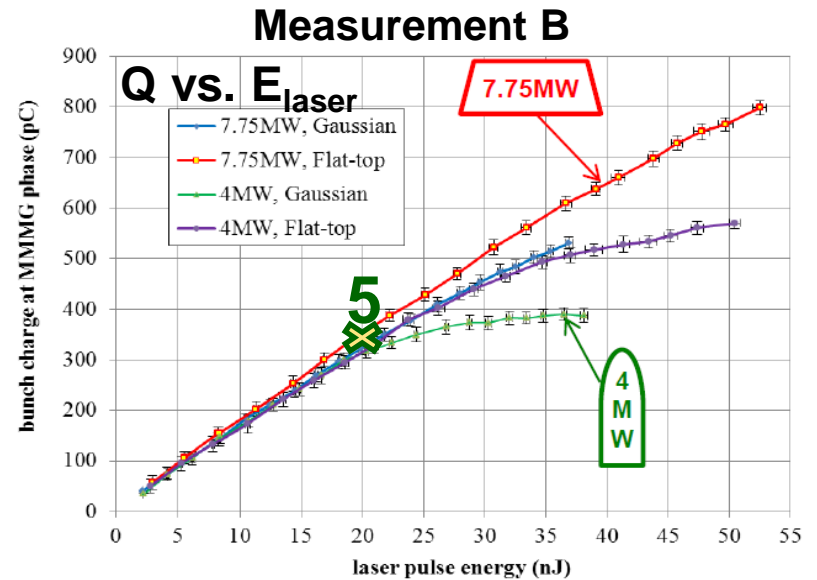
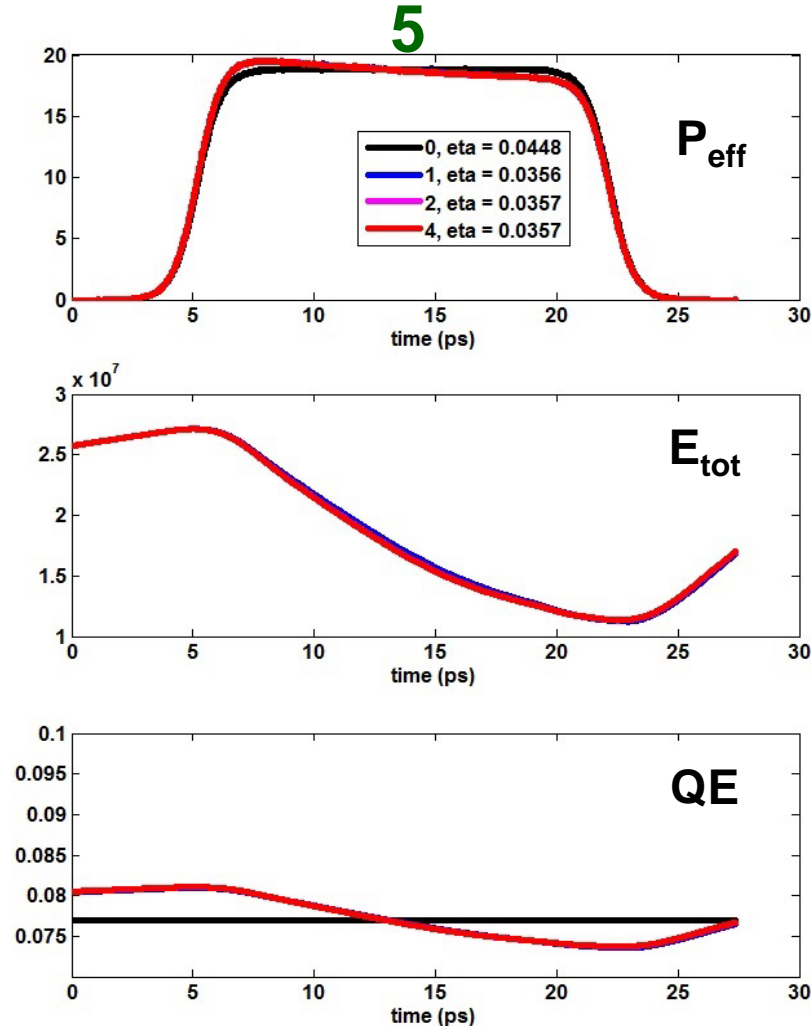


7 MW RF  
Power

	$E_{\text{laser}}$ (nJ)	$E_{\text{cath}}$ (MV/m)	$\eta$
3	37	~46	0.0349
4		~63	0.0351

# Simulation Results: applying to different laser energies

## iteration evolution of main parameters



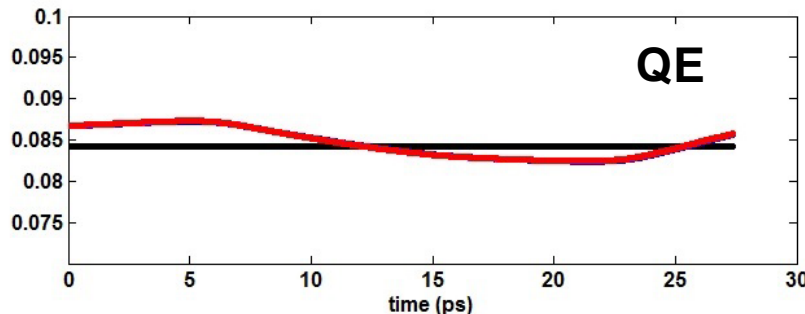
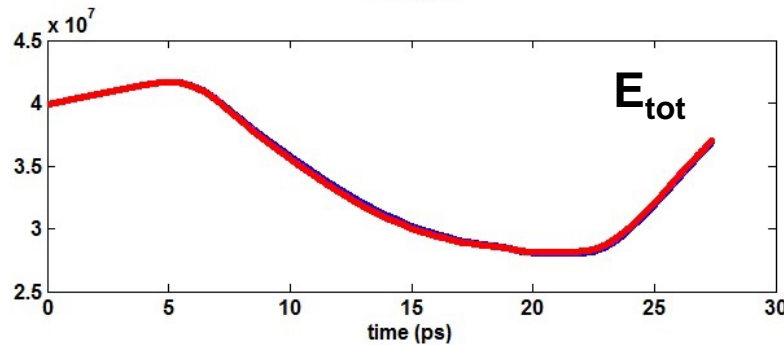
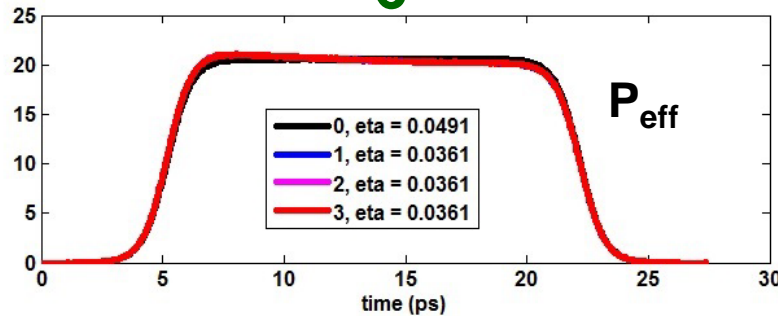
**4 MW RF  
Power**

	$E_{\text{laser}}$ (nJ)		$\eta$
<b>5</b>	<b>20</b>	<b>FT + 4 MW</b>	<b>0.0357</b>

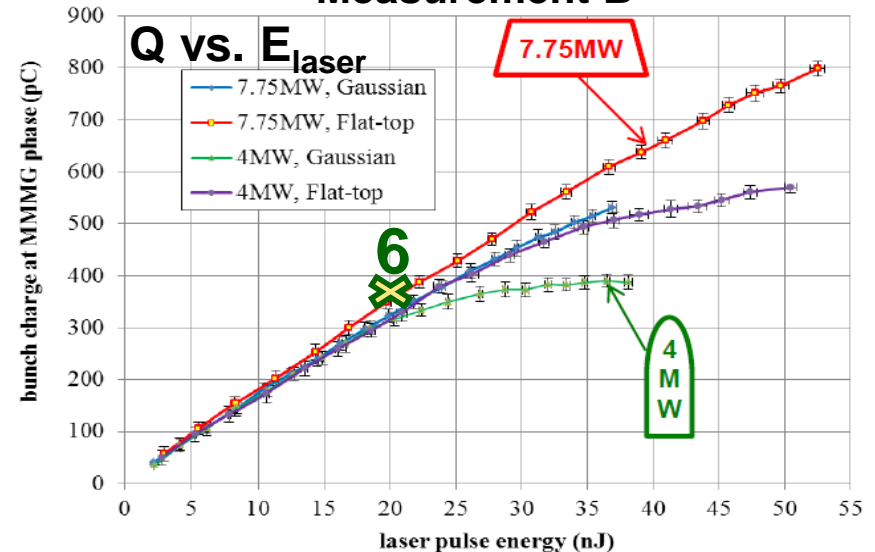
# Simulation Results: applying to different laser energies

iteration evolution of main parameters

6



Measurement B

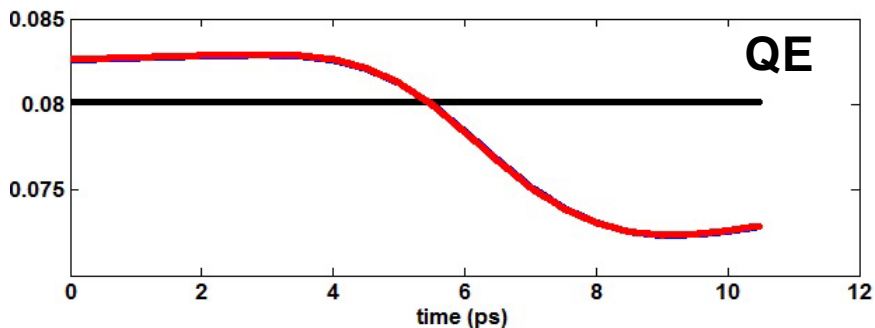
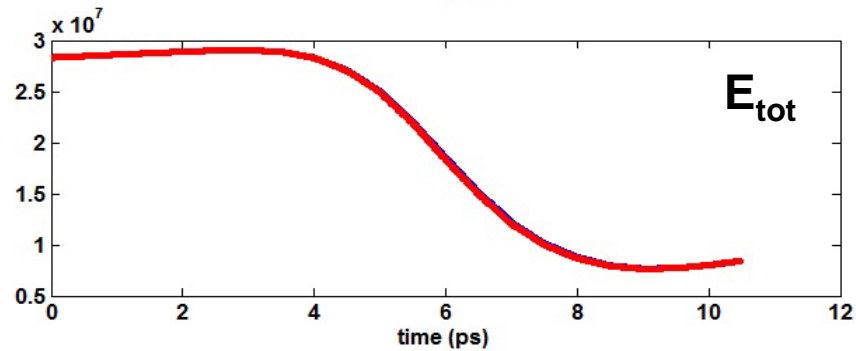
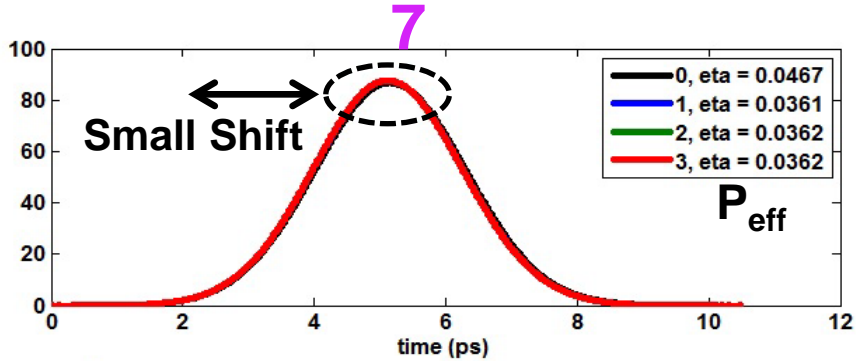


7 MW RF  
Power

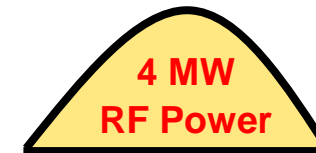
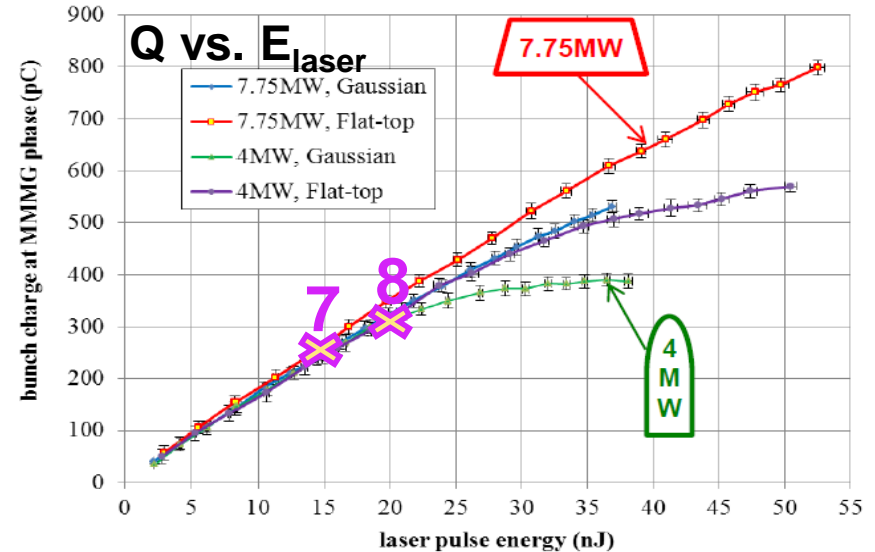
	$E_{\text{laser}}$ (nJ)		$\eta$
6	20	FT + 7.75 MW	0.0361

# Simulation Results: applying to different laser profiles(Gaussian)

## iteration evolution of main parameters



## Measurement B

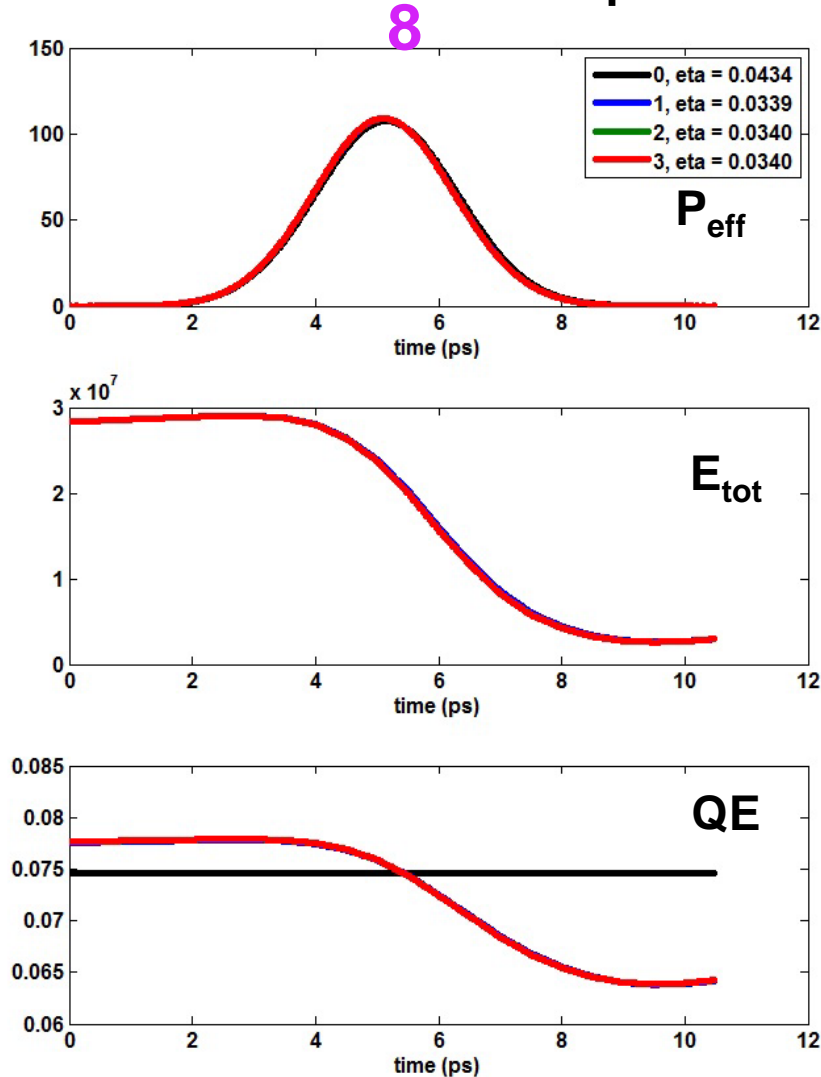


	$E_{\text{laser}}$ (nJ)	$\eta$
<b>7</b>	<b>15</b>	<b>0.0362</b>

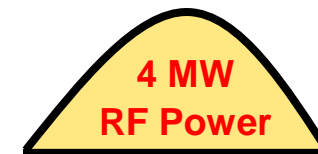
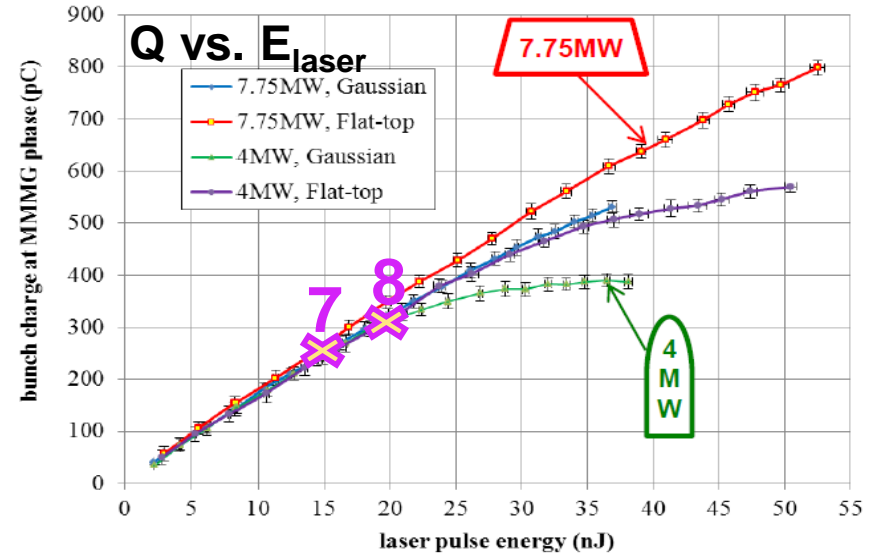


# Simulation Results: applying to different laser profiles

## iteration evolution of main parameters



## Measurement B



	$E_{\text{laser}}$ (nJ)	$\eta$
<b>8</b>	<b>20</b>	<b>0.0340</b>

# At QE-Limited Regime

	Profile	RF Power	$E_{\text{laser}}$	$\eta$
1	FT	4 MW	37 nJ	<b>0.0372</b>
2	FT	4 MW	37 nJ	<b>0.0383</b>
3	FT	7.75 MW	37 nJ	<b>0.0349</b>
4	FT	7.75 MW	37 nJ	<b>0.0351</b>
5	FT	4 MW	20 nJ	<b>0.0357</b>
6	FT	7.75 MW	20 nJ	<b>0.0361</b>
7	GS	4 MW	15 nJ	<b>0.0362</b>
8	GS	4 MW	20 nJ	<b>0.0340</b>

$$\bar{\eta} \approx 0.0359$$

$$\frac{\eta_i - \bar{\eta}}{\eta_i} \times 100 < 6.3\%$$

- $\eta$  found by simulations for 2 temporal profiles, 2 gun powers, 3 laser energies and several field gradients, are quite close to each other, which indicates the emission model works well in the QEL Regime!!

# Intermediate Summary

TABLE II. **QE of the Photocathodes at PITZ** A for use at

Cathode #	Reflectivity at 543 nm	Cleaning process	Deposition date	QE at 254 nm	QE at 262 nm
58.1	56.9%	Standard	December 17, 2004	10.2%	...
34.6	56.5%	CO <sub>2</sub>	December 15, 2006	11.5%	7.5%
42.3	55.8%	Standard	April 5, 2007	11.5%	...
83.3 <sup>a</sup>	56.1%	CO <sub>2</sub>	December 22, 2006	12.0%	7.9%
90.1	56%	Standard	April 3, 2007	9.5%	...
109.1	57%	Standard	April 2, 2007	6.2%	...

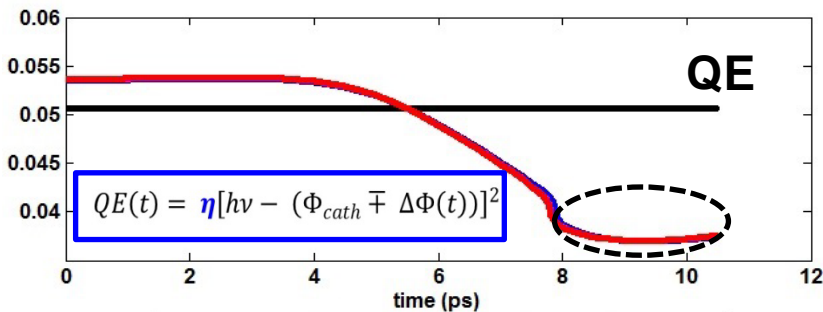
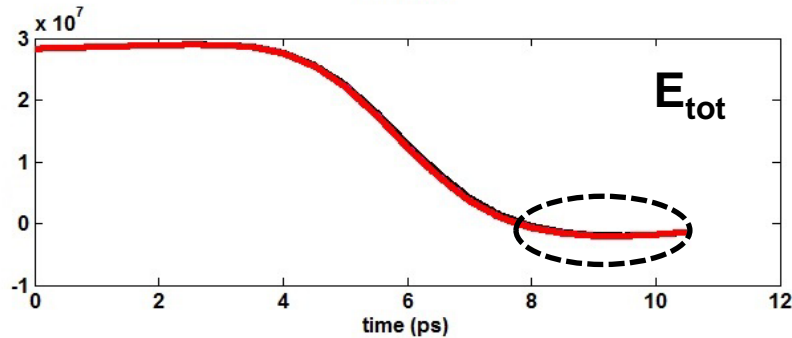
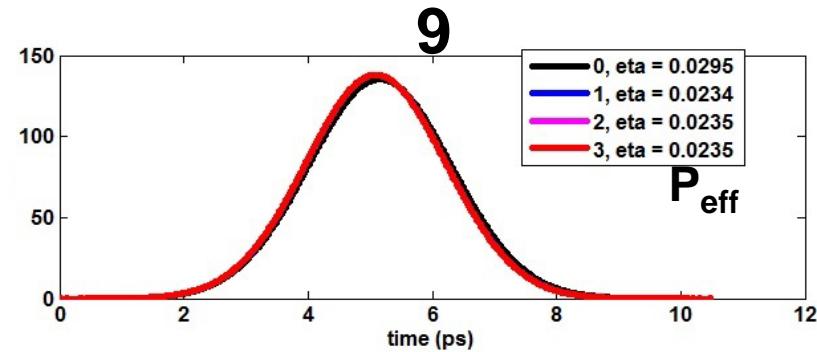
1. **The time-dependent emission model** well predicted the total bunch charge in the QEL regime for full range of machine parameters.
2. **Self-consistent simulation loop** has been designed and applied to study the longitudinal beam dynamics.
3. **Predicted QE** are comparable with the experimental findings.

# From QEL to SCL

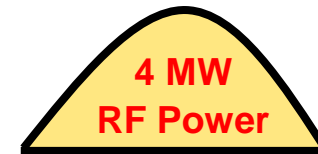
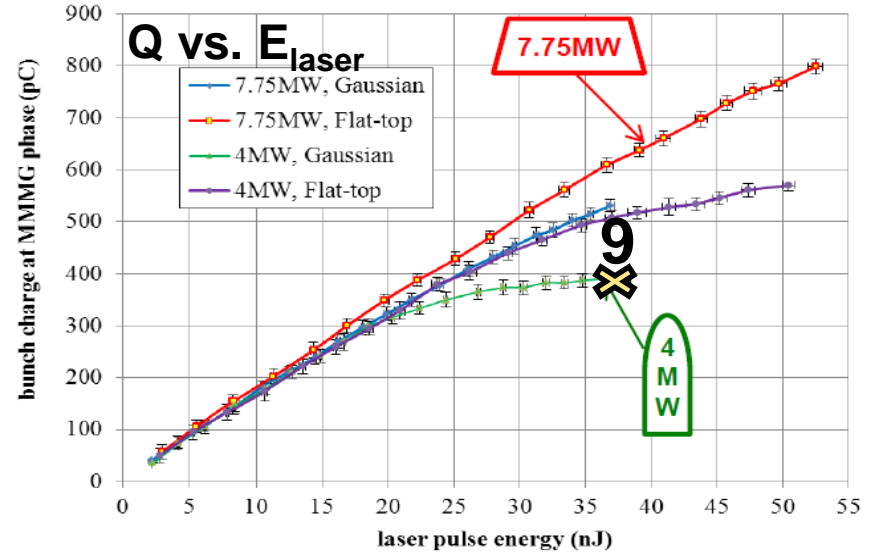
What happens if applying the model to the case close/at SCL?



## iteration evolution of main parameters



## Measurement B



	$E_{\text{laser}}(\text{nJ})$	$\eta$
9	37	0.0235

$\eta$  is smaller than in the QEL regime!!



# From QEL to SCL

$$QE(t) = \eta [h\nu - (\Phi_{cath} \mp \Delta\Phi(t))]^2 \quad (1)$$

$$\Delta\Phi(t) = \sqrt{\frac{e^3}{4\pi\epsilon_0} E_{cath}(z=0, t)} \quad (2)$$

$$Q(t) = \int_{-\infty}^t e \frac{P_{laser}(\tau)}{h\nu} QE(\tau) d\tau \quad (3)$$

	$E_{laser}$ (nJ)		$E_{cath}$ (MV/m)	$\eta$
9	37	GS + 4 MW RF Power	~29.8	0.0235
10		FT + 4 MW RF Power	~19.7	0.0240
11		FT + 7.75 MW RF Power	~17	0.0230

- $\eta$  smaller than in QEL regime, which means the QEL model predicts more charge at the space charge limit. → Unphysical
- The reason is, that Eq. (3) should be normalized to the totally produced charge at the cathode, but at the space charge limit,  $Q_{meas} = Q_{scl} < Q_{QEL}$  !!!
- Even so, the QEL model gives the same  $\eta$  at space charge limits under different situations, which again indicates the model itself is correct !!!

# Intermediate Summary

1. **The bunch charge at the space charge limit predicted by the QEL emission model, should be normalized to the total produced charge at the cathode.**
2. **Same  $\eta$  is given by the QEL emission model even for different space charge limits, which indicates the model is correct.**
3. **Ongoing work to generalize the emission model which also works in the SCL regime. Until then, one can refer to our previous charge iteration algorithm for the SCL bunch charge.**

# Summary and Perspective

## – SC-Limited Regime

- **Self-consistent emission model of CST-PS** can well predict the total bunch charge in the SCL regime for full range of machine parameters.
- **Bunch Charge Iteration Algorithm has been proposed and applied to SCL charge simulations.**
- **Simulation predictions of the bunch spot size** well fit the theory of SCL emission, which suggests the shifting problem at EMSY1 is likely from the experimental issues.

## – QE-Limited Regime

- **The time-dependent emission model** works well in the QEL regime for distinct experimental conditions.
- **Temporal Profile Iteration Algorithm** was proposed and used to QEL charge simulations.
- **Ongoing work** to generalize the emission model which works for SCL and QEL regime in the meantime.

# Reference

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3. J. W. Luginsland et al., Physics of Plasmas Vol. 9, No.5 (2002)
4. D. Filippetto et al., PRST-AB 17, 024201 (2014)
5. David H. Dowell et al., PRST-AB 12, 074201 (2009)
6. Computer Simulation Technology AG, <http://www.cst.com/>

***Thank you for your attention!***